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Selected Papers from Modelica Conference 2021

Guest Editors:

Message from the Guest Editors

Dr. Martin Sjölund

Dear Colleagues,

Prof. Dr. Peter Fritzson

The Modelica Conference is the main event for users.

Dr. Lena Buffoni

Dr. Adrian Pop

Dr. Lennart Ochel

library developers, tool vendors, and language designers to share their knowledge and learn about the latest scientific and industrial progress related to Modelica, the Functional Mockup Interface (FMI), System Structure and Parametrization (SSP), Distributed Co-Simulation Protocol (DCP), and eFMI.

Deadline for manuscript submissions:

closed (15 October 2022)

Since the start of the collaborative design work for Modelica in 1996, Modelica has matured from an idea among a small number of dedicated enthusiasts to a widely accepted standard language for the modeling and simulation of cyber-physical systems.

Modelica is the language of choice for model-based systems engineering and is now used in many industries, including automotive, energy and process, aerospace, and industrial equipment.

This Special Issue aims to collect the conference extension paper from Modelica Conference 2021. Welcome to Contribute.











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Editor-in-Chief

Prof. Dr. Flavio Canavero

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Message from the Editor-in-Chief

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